

## PRODUCT / PROCESS CHANGE NOTIFICATION

### 1. PCN basic data

1.1 Company	 STMicroelectronics International N.V
1.2 PCN No.	MDG/23/14392
1.3 Title of PCN	ST MUAR (Malaysia) die attach material (Glue) additional source for STM32 LQFP 14x14 SHD 100L package - Addendum to PCN13410 to cover more commercial products.
1.4 Product Category	STM32 in LQFP 14x14 SHD 100L package - added devices
1.5 Issue date	2023-11-15

### 2. PCN Team

2.1 Contact supplier	
2.1.1 Name	ROBERTSON HEATHER
2.1.2 Phone	+1 8475853058
2.1.3 Email	heather.robertson@st.com
2.2 Change responsibility	
2.2.1 Product Manager	Ricardo Antonio DE SA EARP
2.2.2 Marketing Manager	Veronique BARLATIER
2.2.3 Quality Manager	Pascal NARCHE

### 3. Change

3.1 Category	3.2 Type of change	3.3 Manufacturing Location
Materials	New direct material part number (same supplier, different supplier or new supplier), Die Attach material	ST MUAR (Malaysia)

### 4. Description of change

	Old	New
4.1 Description	STM32 LQFP 14x14 SHD 100L package current die attach material is glue Loctite Ablestik ABP8302	STM32 LQFP 14x14 SHD 100L package Die attach material : - glue Loctite Ablestik ABP8302 - current - glue Hitachi EN4900GC - additional
4.2 Anticipated Impact on form, fit, function, quality, reliability or processability?	no impact	

### 5. Reason / motivation for change

5.1 Motivation	For STM32 LQFP 14x14 SHD 100L additional devices listed in PCN14392 we can replace the GLUE LOCTITE ABLESTIK ABP8302 by GLUE HITACHI EN4900GC since this Glue is already used in production for product impacted by PCN13410.
5.2 Customer Benefit	SERVICE IMPROVEMENT

### 6. Marking of parts / traceability of change

6.1 Description	Traceability ensured by ST internal tool
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### 7. Timing / schedule

7.1 Date of qualification results	2023-05-19
7.2 Intended start of delivery	2023-12-20
7.3 Qualification sample available?	Upon Request

### 8. Qualification / Validation

8.1 Description	14392 MDG-MCD RER1514- LQFP7x7 Muar-PCN9484- reliability evaluation report.pdf		
8.2 Qualification report and qualification results	Available (see attachment)	Issue Date	2023-11-15

**9. Attachments (additional documentations)**

14392 Public product.pdf  
14392 MDG-MCD RER1514- LQFP7x7 Muar-PCN9484- reliability evaluation report.pdf  
14392 PCN14392\_Additional information.pdf

**10. Affected parts**

<b>10. 1 Current</b>		<b>10.2 New (if applicable)</b>
<b>10.1.1 Customer Part No</b>	<b>10.1.2 Supplier Part No</b>	<b>10.1.2 Supplier Part No</b>
	STM32F100VCT6	
	STM32F100VDT6	
	STM32F100VET6	
	STM32F105VCT6V	
	STM32F105VCT6W	

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**PCN Title :** ST MUAR (Malaysia) die attach material (Glue) additional source for STM32 LQFP 14x14 SHD 100L package - Addendum to PCN13410 to cover more commercial products.

**PCN Reference :** MDG/23/14392

**Subject :** Public Products List

Dear Customer,

Please find below the Standard Public Products List impacted by the change.

STM32F100VET6	STM32F100VCT6	STM32F105VCT6W
STM32F105VCT6V	STM32F100VDT6	STM32F103VGT6J

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# MMS- MCD RER1514

## Reliability Report

Qualification Type : ASSEMBLY LINE QUALIFICATION, NEW BILL OF MATERIALS

### LQFP 7x7 48L - ST Muar Qualification

### Dice 410/427/765

(PCN MMS-MIC/15/9484 dated 30 Oct 2015)

Product / Process & Package Information	Die 410	Die 427	Die 765
Commercial Product:	STM32F103CBT6	STM32L152CCT6	STM8S207C8T6
Product Line:	STM32F die 410	STM32L die 427	STM8S die 765
Product Description:	Micro 32Bits		Micro 8Bits
Finish Good Code:	ES32F103CBT6\$J8	ES32L152CCT6\$B6	ES8S207C8T6\$9C
Mask Set Revision:	X410XXXX	X427XXXV	X765XXXV
Silicon Process Technology:	0.18 M8 EMBEDDED FLASH	8X - CMOSF9S	2V - CMOSF9
Wafer Fabrication Location:	TSMC Fab 3 Taiwan	ST Rousset 8 France	ST Rousset 8 France
Electrical Wafer Sort Test Plant Location:	ST MICROELECTRONICS Ang Mo Kio EWS SINGAPORE		ARDENTEC Hsinchu EWS Taiwan
Package:	LQFP 48 7x7x1.4		
Assembly Plant location:	ST Muar (Malaysia)		
Final Test plant location:	ST Muar (Malaysia)		

Approval List			
Function	Location	Name	Date
Division Q&R Responsible	ST Rousset	Gisèle SEUBE	May31st, 2016
Division Quality Manager	ST Rousset	Pascal NARCHE	May31st, 2016

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# 1 RELIABILITY RESULTS OVERVIEW

## 1.1 Objectives

This report summarizes the reliability results for LQFP 48 7x7 package manufactured at ST Muar (Malaysia).

Test vehicles are described here below:

Product	Package
STM32F103CBT6	LQFP 48 7x7x1.4
STM32L152CCT6	LQFP 48 7x7x1.4
STM8S207C8T6	LQFP 48 7x7x1.4

## 1.2 Context

In order to increase assembly capacity, ST Microcontrollers Division has decided to add a High Density line in ST Muar (Malaysia) assembly site, for LQFP 48 7x7 products.

New Bill of Materials changes are described here below for LQFP 7x7 48L products:

	Existing Bill Of Materials			Added Bill Of Materials
	STATS Shanghai (China)	ChipPAC	Amkor ATP (Philippines)	ST Muar (Malaysia)
Wire	Gold 0.8mil	Gold 0.8mil	Gold 0.8mil	Silver 0.8mil
Leadframe	Copper Spot Ag	Frame	Copper Frame Spot Ag	Pre Plated Frame
Leadfinishing (*1)	Pure Tin (e3)	Pure Tin (e3)	Rough Ni Pd AgAu (e4)	Rough Ni Pd AgAu (e4)
Resin	Sumitomo G700E	Sumitomo G631HQ	Sumitomo G700LS	Sumitomo G700LS
Glue	Ablestik 3230	Evertech AP4200	Hitachi EN4900	Hitachi EN4900

According to the positive reliability results, the qualification is granted for High Density assembly line in ST Muar (Malaysia).

## 2 RELIABILITY TEST VEHICLES Characteristics

### 2.1 Reliability Test vehicles description

Package line	Assembly Line	Package	Device (Partial RawLine Code)	Diffusion Process	Number of Lots
HD LQFP	LQFP7*7	48L	STM8S (5B*765) STM32F (5B*410) STM32L (5B*427)	F9GO1 TSMC 0.18µm F9GO2S	1 1 1

### 2.2 Reliability Information

Lot ID	Lot 1	Lot 2	Lot 3
Die Name /cut:	410	427	765
Diffusion Lot Number:	93537129	VG536347	VG540309
Trace Code:	995510CH	995510CQ	995510CR
Assy lot number	995510CH01	995510CQ01	995510CR01
Raw Line Code Package:	J55B*410ESXX	U05B*427ESXV	J15B*765ESXV
Reliability Lab location :	ST Muar (Malaysia)		

## 2.3 Front-End information

Front-End	Lot 1 (410)	Lot 2 (427)	Lot 3 (765)
<b>Wafer Diameter:</b>		8 inches	
<b>Wafer Thickness:</b>		375 +/-25 µm	
<b>Die Size:</b>	3.3908 X 3.328 mm	3.263 X 4.199 mm	3.010 X 2.458 mm
<b>Scribe Line size x/y:</b>		80 x 80 µm	
<b>Pad Die Size /Pad type:</b>	59 x 123 µm	53 x 108 µm	65 x 108 µm
<b>Metal Layers Number /Materials /Thickness:</b>	Metal 1 Tin/AlCu/Tin 0.450 µm Metal 2 Tin/AlCu/Tin 0.450 µm Metal 3 Tin/AlCu/Tin 0.450 µm Metal 4 Tin/AlCu/Tin 0.450 µm Metal 5 Tin/AlCu/Tin 0.875 µm	Metal 1 TaN/Ta/Cu 0.280 µm Metal 2 Ti/AlCu/TxTN 0.310 µm Metal 3 Ti/AlCu/TxTN 0.310 µm Metal 4 Ti/AlCu/TxTN 0.310 µm Metal 5 Ti/AlCu/TxTN 1.200 µm	Metal 1 TaN/Ta/Cu 0.280 µm Metal 2 TaN/Ta/Cu 0.350 µm Metal 3 TaN/Ta/Cu 0.350 µm Metal 4 Ti/AlCu/TxTN 0.900 µm
<b>Passivation Layers Thickness:</b>	HDPOx 10kA+SRO 1.5kA+PESIN 6kA		USG + NitUV (HFP USG+UV Nitride)
<b>Back Metal Finishing</b>	RAW SILICON - BACK GRINDING		

## 2.4 Back-End information

Back-End	Lot 1 (410)	Lot 2 (427)	Lot 3 (765)
<b>Assembly Plant Location/ Address:</b>	ST MICROELECTRONICS TANJONG AGAS IND ESTATE PO BOX 28 84007 MUAR / JOHOR MALAYSIA		
<b>Die Thickness after Back grinding:</b>	NA	NA	NA
<b>Die sawing method:</b>	Step cut		
<b>Die attach material:</b>	Glue EN4900		
<b>Type:</b>	ST16		
<b>Supplier:</b>	Hitachi		
<b>Lead frame material:</b>	Copper LF-HD LQFP 48L 7x7		Copper LF-HD LQFP 48L 7x7
<b>L/F Finishing Type:</b>	Rough µPPF (e4) Ni Pd AuAg		Rough µPPF (e4) Ni Pd AuAg
<b>Die paddle size:</b>	5 x 5		3.6 x 3.6
<b>Supplier:</b>	HDS		HDS
<b>Wire bonding:</b>	AG 96,5% WIRE 0.8MIL MKE		
<b>Type /Diameter:</b>			
<b>Supplier:</b>			
<b>Pitch:</b>	80µm	70µm	80,36µm
<b>POA:</b>	0110596		
<b>Molding Compound Supplier:</b>	EME-G700LS SUMITOMO		
<b>Package Moisture Sensitivity Level (JEDEC J-STD020D):</b>	2		

### 3 RELIABILITY RESULTS SUMMARY

#### 3.1 Die oriented test

		Die Related Tests					Results LQFP 7x7		
Description	Test/Method	Conditions	Sample Size	Criteria	Readout / Duration	410	427	765	
<i>Electrostatic discharge – Charge Device Model</i>									
ESD CDM	ANSI/ESD STM5.3.1	500V 1KV	3 units	500V for dice 410/427 1KV for 765	NA	0/3	0/3	0/3	

#### 3.2 Package Oriented Test

		Package Related Tests					Results LQFP 7x7		
Description	Test/Method	Conditions	Sample Size	Criteria	Readout / Duration	410	427	765	
<i>Preconditioning: moisture sensitivity level 1</i>									
PC	J-STD-020 JESD22-A113	MSL1 For MSL2 Qual	308 units	Electrical test: A0/R1 (Accepted 0 reject/ Rejected 1 reject)	NA	0/308			
<i>High Temperature Storage Life</i>									
HTSL	JESD 22-A103	150°C	77 units	Elect test A0/R1	1000h	0/77	0/77	0/77	
<i>Thermal Cycling after Preconditioning</i>									
TC	JESD 22-A104	-65c/+150°C	77 units	Elect test A0/R1	100cy	0/77	0/77	0/77	
					500cy	0/77	0/77	0/77	
					1000cy	0/77	0/77	0/77	
<i>Wire Bond Shear after Thermal Cycling</i>									
Wire Bond Shear	AEC Q100-001	Min bond shear 15g after TC	30 x 3	A0/R1	After TC 500cy TC 1000cy	0/30	0/30	0/30	
<i>Wire Bond Pull after Thermal Cycling</i>									
Wire Bond Pull	Mil Std 883 Method 2011	Minimum pull strength after TC=3 grams after TC	30 x 3	A0/R1	After TC 500cy TC 1000cy	0/30	0/30	0/30	

Autoclave after Preconditioning								
AC	JESD 22A102	121°C ,100% 2Atm RH	77 units	Elect test A0/R1	96h	0/77	0/77	0/77
Temperature Humidity Bias after Preconditioning								
THB	JESD 22A110	85°C/85%RH Bias	77 units	Elect test A0/R1	1000h	0/77	0/77	0/77
Construction Analysis								
CA	Construction Analysis including : -Wire bond shear -Wire bond pull -Solderability -Physical Dimension	JESD 22B102 JESDB100/B108	50		No major concern	No major concern		

## 4 APPLICABLE AND REFERENCE DOCUMENTS

<b>ADCS/DMS 0061692 :</b>	Reliability Tests And Criteria For Qualifications
<b>SOP 2.6.2:</b>	Process qualification and transfer management
<b>SOP 2.6.7:</b>	Product Maturity Level
<b>SOP 2.6.9:</b>	Package and process maturity management in Back End
<b>SOP 2.6.11:</b>	Program management from product qualification
<b>SOP 2.6.19:</b>	Process maturity level
<b>ANSI-ESD STM5.3.1:</b>	Electrostatic discharge (ESD) sensitivity testing charge device model (CDM)
<b>JESD 22-A103</b>	High Temperature Storage Life
<b>J-STD-020D:</b>	Moisture/reflow sensitivity classification for non-hermetic solid state surface mount devices
<b>JESD22-A113:</b>	Preconditioning of non-hermetic surface mount devices prior to reliability testing
<b>JESD22-A102:</b>	Autoclave test (pressure pot)
<b>JESD22-A104:</b>	Temperature cycling
<b>JESD22-A110:</b>	Temperature Humidity Bake
<b>JESD 22B102:</b>	Solderability test
<b>JESD22B100/B108:</b>	Physical dimension

## 5 GLOSSARY AND TESTS DESCRIPTION

<b>PC</b>	Preconditioning (solder simulation)
<b>THB</b>	Temperature Humidity Bias
<b>TC</b>	Temperature cycling
<b>AC</b>	Autoclave test (pressure pot)
<b>HTSL</b>	High temperature storage life
<b>ADCS/DMS</b>	ST Advanced Documentation Controlled system/ Documentation Management system
<b>ESD CDM</b>	Electrostatic discharge (charge device model)
<b>CA</b>	Construction Analysis

## 6 REVISION HISTORY

Version	Date	Author	Comment
1.0	May 31st, 2016	Olivier GIRAUD	Initial release for qualification

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**PRODUCT/PROCESS  
CHANGE NOTIFICATION  
PCN14392  
– Additional information**

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**ST MUAR (Malaysia) die attach material (Glue) additional source  
for STM32 LQFP 14x14 SHD 100L package - Addendum to  
PCN13410 to cover more commercial products.**

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**MDG - Microcontrollers Division (MCD)**

**What are the changes?**

This PCN is an addendum to previous PCN13410 to cover more Commercial Products impacted by the same change and align all the production to this new change.

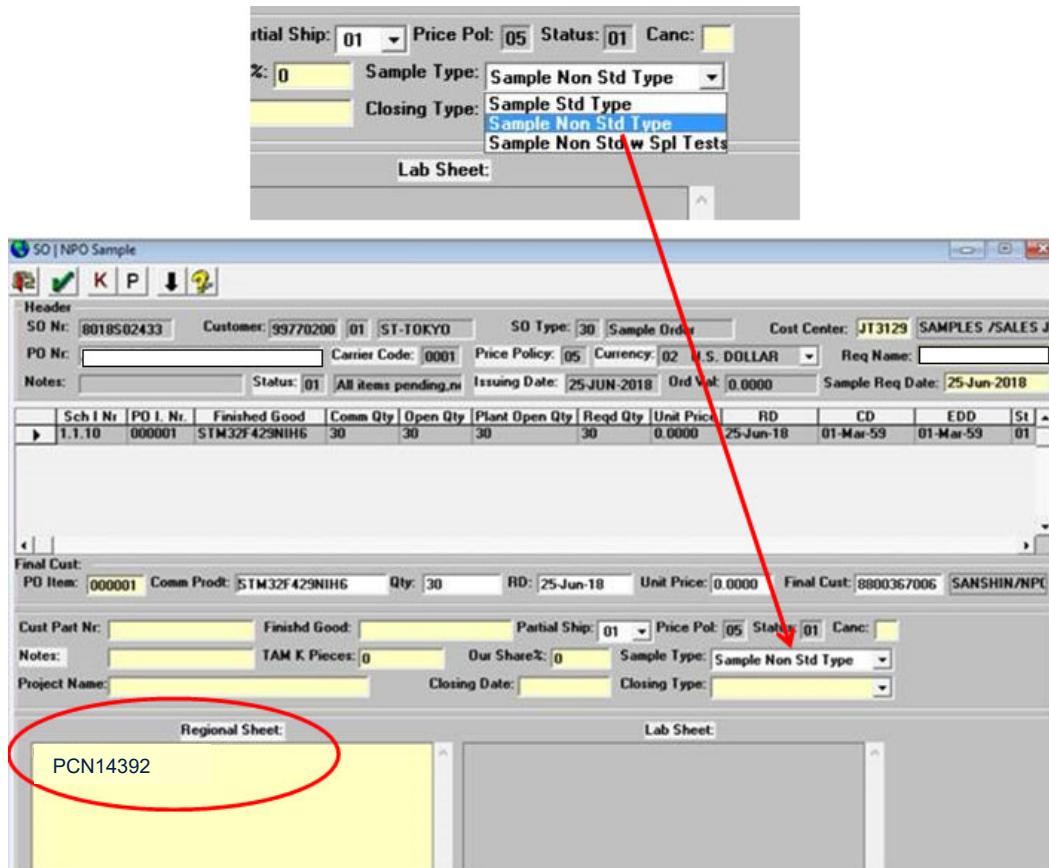
Changes described in table below:

	Existing back-end lines	Added back-end line
Assembly site		ST Muar Malaysia
Die Attach Material	GLUE LOCTITE ABLESTIK ABP8302	GLUE HITACHI EN4900GC

## How to order samples?

For all samples request linked to this PCN, please:

- place a Non-standard sample order (choose Sample Non Std Type from pull down menu)
- insert the PCN number “**PCN14392**” into the NPO Electronic Sheet/Regional Sheet
- request sample(s) through Notice tool, indicating a single Commercial Product for each request



SO | NPO Sample

Header

SO Nr: 8018502433 Customer: 39770200 01 ST-TOKYO SO Type: 30 Sample Order Cost Center: JT3129 SAMPLES /SALES J

PO Nr: Carrier Code: 0001 Price Policy: 05 Currency: 02 U.S. DOLLAR Req Name:

Notes: Status: 01 All items pending, no Issuing Date: 25-JUN-2018 Ord Val: 0.0000 Sample Req Date: 25-Jun-2018

Sch I Nr	PO I. Nr.	Finished Good	Comm Qty	Open Qty	Plant Open Qty	Reqd Qty	Unit Price	RD	CD	EDD	St
1.1.10	000001	STM32F429NIH6	30	30	30	30	0.0000	25-Jun-18	01-Mar-59	01-Mar-59	01

Final Cust:

PO Item: 000001 Comm Prod: STM32F429NIH6 Qty: 30 RD: 25-Jun-18 Unit Price: 0.0000 Final Cust: 8800367006 SANSHIN/NPC

Cust Part Nr: Finished Good: Partial Ship: 01 Price Pol: 05 Status: 01 Canc:

Notes: TAM K Pieces: 0 Our Share%: 0 Sample Type: Sample Non Std Type

Project Name: Closing Date: Closing Type:

Regional Sheet: **PCN14392**

Lab Sheet:



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